

**Search Notes**

Application/Control No.

10/780,607

Examiner

Raymond Phan

Applicant(s)/Patent under  
Reexamination

TAKEDA ET AL.

Art Unit

2111

**SEARCHED**

Class	Subclass	Date	Examiner
710	309- 315,111- 113,36-39	6/14/2006	RP
710	7-8,52-54	6/14/2006	RP
710	240-241	6/14/2006	RP
711	167-169	6/15/2006	RP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
710	310,309	6/20/2006	RP

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consult with Paul Myer (2112)	6/13/2006	RP
EAST	6/17/2006	RP